## Application/Control No. O9/749,917 Applicant(s)/Patent Under Reexamination CHANG ET AL. Examiner Nikolas J. Uhlir Applicant(s)/Patent Under Reexamination CHANG ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification		
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	В	US-					
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## **NON-PATENT DOCUMENTS**

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